# **Power MOSFET**

# 28 V, 14 A, N-Channel, SOIC-8

#### **Features**

- Low R<sub>DS(on)</sub>
- High Power and Current Handling Capability
- Low Gate Charge
- Pb-Free Package is Available

### **Applications**

- DC/DC Converters
- Motor Drives
- Synchronous Rectifier POL
- Buck Low-Side

#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Drain-to-Source Voltage	$V_{DSS}$	28	V
Gate-to-Source Voltage - Continuous	$V_{GS}$	± 20	V
Drain Current Continuous @ $T_A = 25^{\circ}C$ (Note 1) Continuous @ $T_A = 25^{\circ}C$ (Note 2) Continuous @ $T_A = 25^{\circ}C$ (Note 3) Single Pulse (tp = 10 $\mu$ s)	I <sub>D</sub>	14 12 9.0 40	Α
Total Power Dissipation $T_A = 25^{\circ}C$ (Note 1) $T_A = 25^{\circ}C$ (Note 2) $T_A = 25^{\circ}C$ (Note 3)	P <sub>D</sub>	2.5 1.66 0.93	W
Operating and Storage Temperature	T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	°C
Single Pulse Drain-to–Source Avalanche Energy – Starting $T_J$ = 25°C ( $V_{DD}$ = 30 V, $V_{GS}$ = 10 V, $I_L$ = 12.2 A, L = 1.0 mH, $R_G$ = 25 $\Omega$ )	E <sub>AS</sub>	75	mJ
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds	T <sub>L</sub>	260	°C

### THERMAL RESISTANCE RATINGS

Rating	Symbol	Value	Unit
Thermal Resistance Junction-to-Ambient (Note 1) Junction-to-Ambient (Note 2) Junction-to-Ambient (Note 3)	$R_{ heta JA}$	50 75 135	°C/W

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

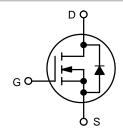
- 1. Surface-mounted on FR4 board using minimum recommended pad size (Cu area 0.412 in sq), t < 10 s.
- Surface-mounted on FR4 board using 1" pad size (Cu area 1.127 in sq) steady state.
- Surface-mounted on FR4 board using minimum recommended pad size (Cu area 0.412 in sq), steady state.



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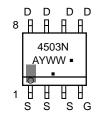
V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> Typ	I <sub>D</sub> Max (Note 1)
28 V	7.0 mΩ @ 10 V	14 A
20 V	8.8 mΩ @ 4.5 V	1474



# MARKING DIAGRAM & PIN ASSIGNMENT



SOIC-8 CASE 751 STYLE 12



4503N = Specific Device Code A = Assembly Location

Y = Year WW = Work Week ■ Pb-Free Package

(Note: Microdot may be in either location)

### ORDERING INFORMATION

Device	Package	Shipping†	
NTMS4503NR2	SOIC-8	2500/Tape & Reel	
NTMS4503NR2G	SOIC-8 (Pb-Free)	2500/Tape & Reel	

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Characteristic	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS					-		-
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		28	31	-	V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>	-		-	22	-	mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V 0.V.V 0.4.V.	T <sub>J</sub> = 25°C	1	_	1.0	μΑ
		$V_{GS} = 0 \text{ V}, V_{DS} = 24 \text{ V}$	T <sub>J</sub> = 100°C	1	_	25	1
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} =$	±20 V	ı	-	± 100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}$ , $I_D = 2$	250 μΑ	1.0	_	2.0	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>	_		1	-5.0	-	mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> =	= 14 A	-	7.0	8.0	mΩ
		V <sub>GS</sub> = 4.5 V, I <sub>D</sub> =	= 10 A	_	8.8	9.8	
Forward Transconductance	9FS	V <sub>DS</sub> = 10 V, I <sub>D</sub> =	= 14 A	-	30	-	S
CHARGES, CAPACITANCES AND GATE RE	SISTANCE				•		
Input Capacitance	C <sub>ISS</sub>			-	2400	-	pF
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1.0 MHz	-	1000	-	1	
Reverse Transfer Capacitance	C <sub>RSS</sub>		-	375	-		
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 16 \text{ V}, I_D = 10 \text{ A}$		-	23	-	nC
Threshold Gate Charge	Q <sub>G(TH)</sub>			-	2.0	-	
Gate-to-Source Charge	Q <sub>GS</sub>			-	5.0	-	1
Gate-to-Drain Charge	$Q_{GD}$			-	12	-	
SWITCHING CHARACTERISTICS, V <sub>GS</sub> = V (	Note 5)						
Turn-On Delay Time	t <sub>d(ON)</sub>			-	18.5	-	ns
Rise Time	tr	VGS = 4.5 V. VDD = 16	V. In = 10 A.	-	70	-	
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DD} = 16$ $R_{G} = 2.0 \Omega$	2	-	21	-	
Fall Time	t <sub>f</sub>			-	23	-	
DRAIN-SOURCE DIODE CHARACTERISTIC	s						
Forward Diode Voltage	ward Diode Voltage $V_{SD}$ $T_{J} = 25^{\circ}C$		$T_J = 25^{\circ}C$	-	0.82	1.2	V
		$V_{GS} = 0 \text{ V, } I_{S} = 10 \text{ A}$ $T_{J} = 125^{\circ}\text{C}$		-	0.65	-	
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V},$ $d_{ISD}/d_t = 100 \text{ A/}\mu\text{s},$ $I_S = 14 \text{ A}$		-	48	-	ns
Charge Time	Ta			-	23	-	1
Discharge Time	T <sub>b</sub>			-	25	-	1
Reverse Recovery Charge	$Q_{RR}$			-	25	_	nC

Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL PERFORMANCE CURVES**

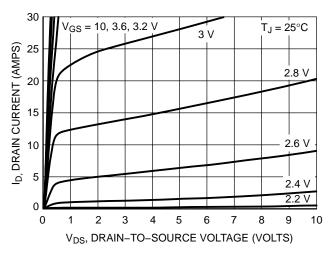


Figure 1. On-Region Characteristics

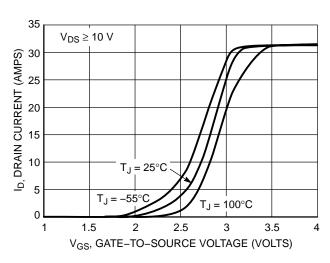


Figure 2. Transfer Characteristics

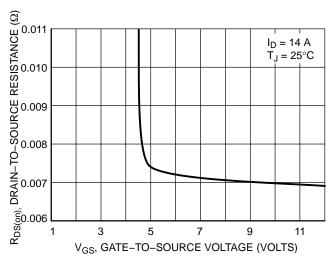


Figure 3. On-Resistance vs. Gate-to-Source Voltage

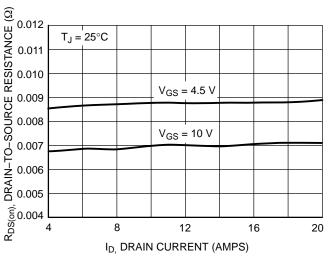


Figure 4. On–Resistance vs. Drain Current and Gate Voltage

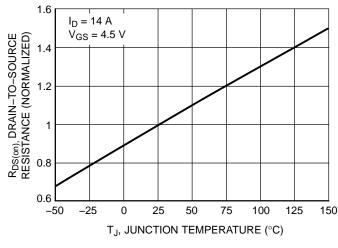


Figure 5. On–Resistance Variation with Temperature

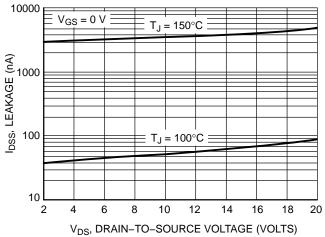
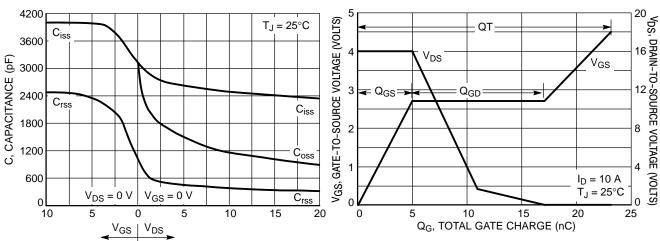


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL PERFORMANCE CURVES**



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 7. Capacitance Variation

Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

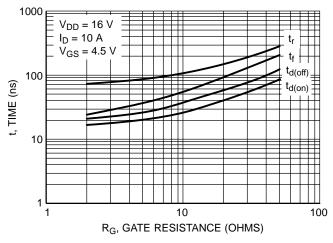


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

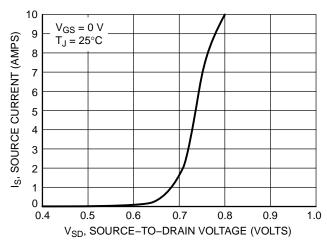
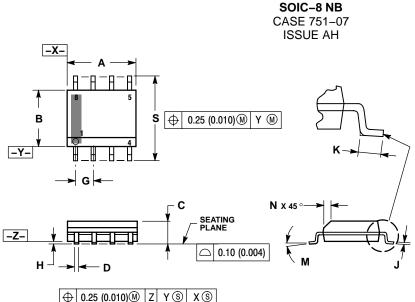
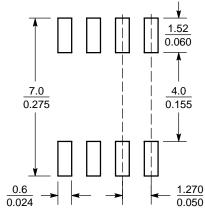


Figure 10. Diode Forward Voltage vs. Current

#### PACKAGE DIMENSIONS



#### SOLDERING FOOTPRINT\*



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					SCAL	E 6:1	$\left(\frac{\text{mm}}{\text{inches}}\right)$
deta	ndditional informils, please down nting Techniq	wnload th	ne ON	Semi	conduc	ctor S	oldering and

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- PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR
  PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751–01 THRU 751–06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIN	IETERS	INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	4.80	5.00	0.189	0.197	
В	3.80	4.00	0.150	0.157	
С	1.35	1.75	0.053	0.069	
D	0.33	0.51	0.013	0.020	
G	1.27 BSC		0.050 BSC		
Н	0.10	0.25	0.004	0.010	
J	0.19	0.25	0.007	0.010	
K	0.40	1.27	0.016	0.050	
M	0 °	8 °	0 °	8 °	
N	0.25	0.50	0.010	0.020	
S	5.80	6.20	0.228	0.244	

#### STYLE 12:

- PIN 1. SOURCE
  - SOURCE 2. SOURCE
  - GATE
  - DRAIN 5
  - DRAIN 6.
  - DRAIN 8 DRAIN